

Presented at
KEKB REVIEW COMMITTEE

Monday, Feb.16, 2004

High Power UHF CW Klystrons for KEKB and One of the Key Techniques

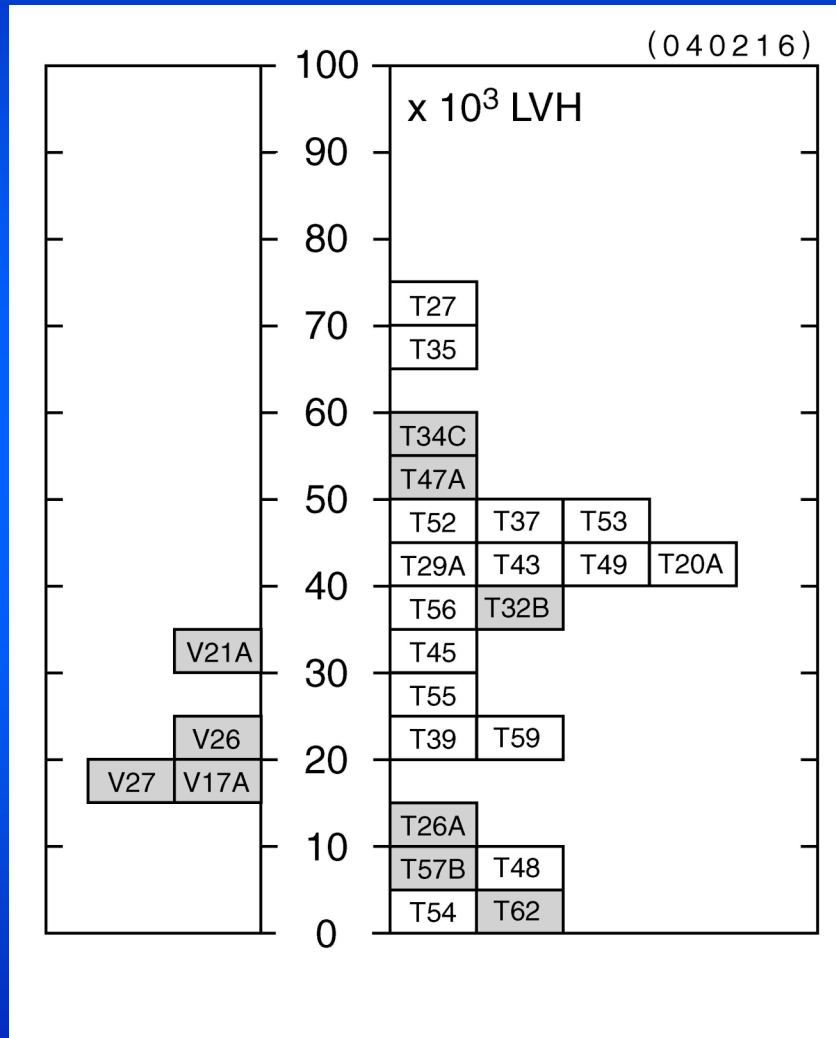
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Present Line-up of CW Klystrons for KEKB(24) and PF-AR(2).

Number of klystron in each LV age category.



V : 1MW tubes from Philips (VALVO).

T : 1.2MW tubes from Toshiba.

V tubes now only being used for half of SC cavities.

Both tubes have been developed and improved originally for TRISTAN in close collaboration between KEK and each industry.

Some tubes are very long life, top runner exceeding 72,000 LVH.

Hatched tubes install M-type (cold) cathode for solving Ba related problems.

Klystron MTBF at KEK

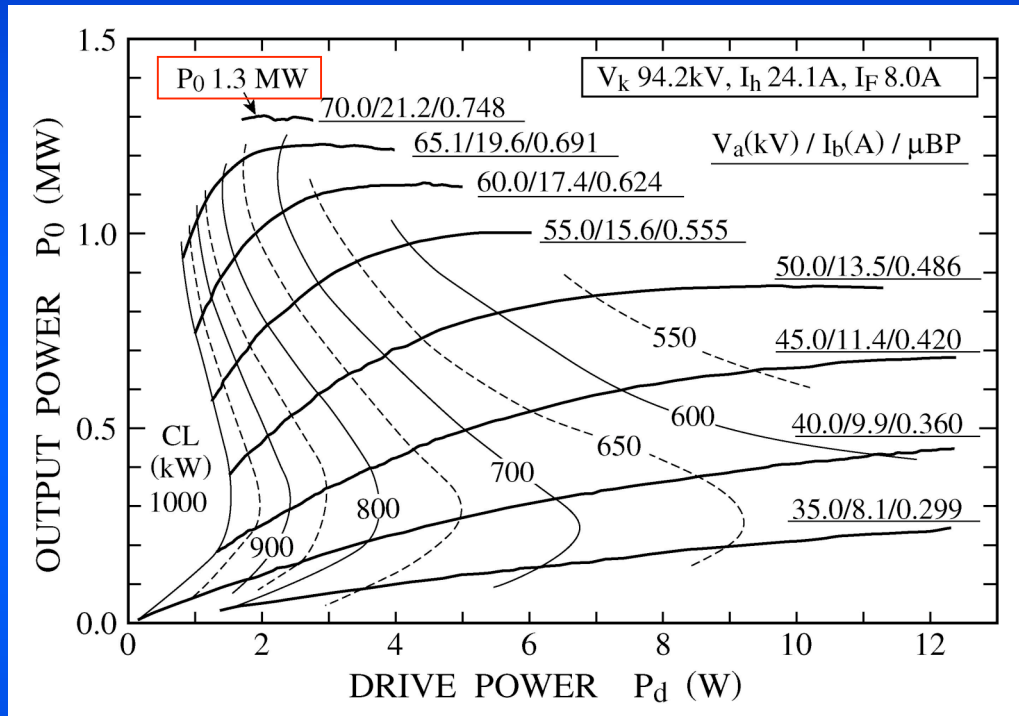
	Power Rating (kW)	Operation Power (kW)	Total LVH (h)	Failures	MTBF (h)
V	800-1,000 CW	150 - 850	543,571.7 (540,143.5)	38 (30)	14,305 (18,005)
T	1,200 CW	350 - 900	1,177,631.8 (1,172,920.4)	34 (25)	34,636 (46,917)

Numbers in parentheses denote the data when initial failures during the period below 1,000 LVH are not included, considering Infant Mortality.

Stable, reliable and long life performances have been assured, which contributed much to KEKB's success.

MTBF : Mean Time Between Failures

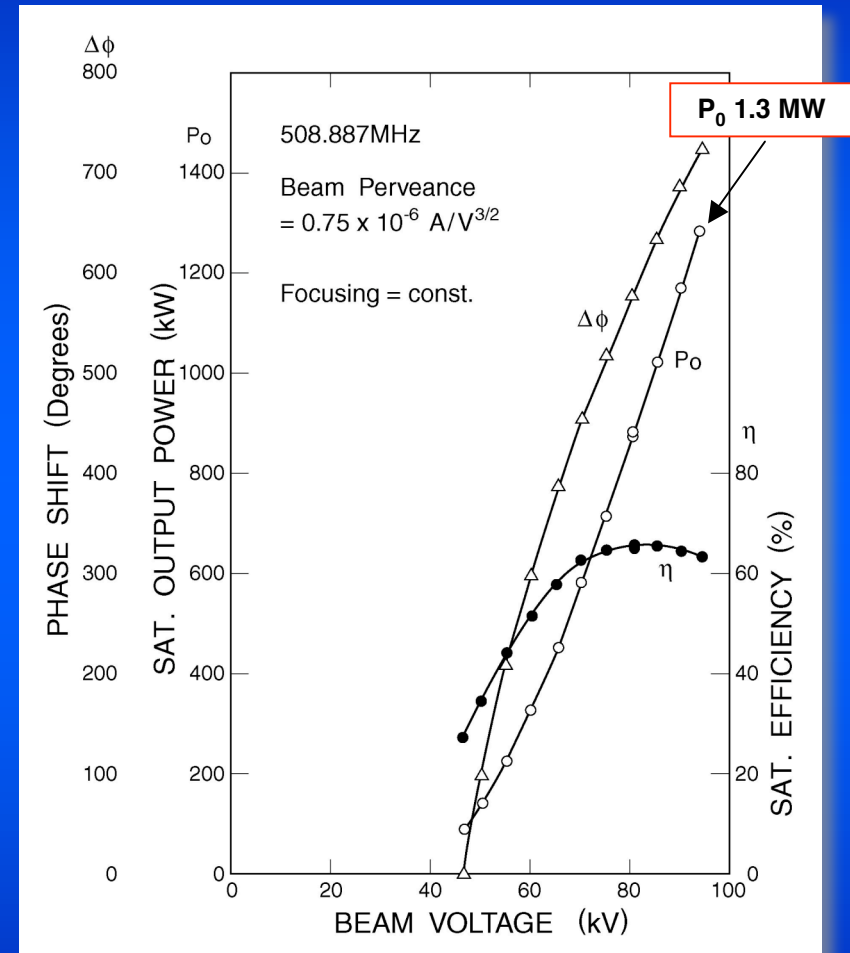
Operation of a T-tube at the World's Highest Power Level (1.3 MW CW)



Klystron characteristics at KEKB frequency, 508.887 MHz. Constant collector loss curves (in kW) are shown up to 1000 kW.

The highest rf output is 1.3 MW.

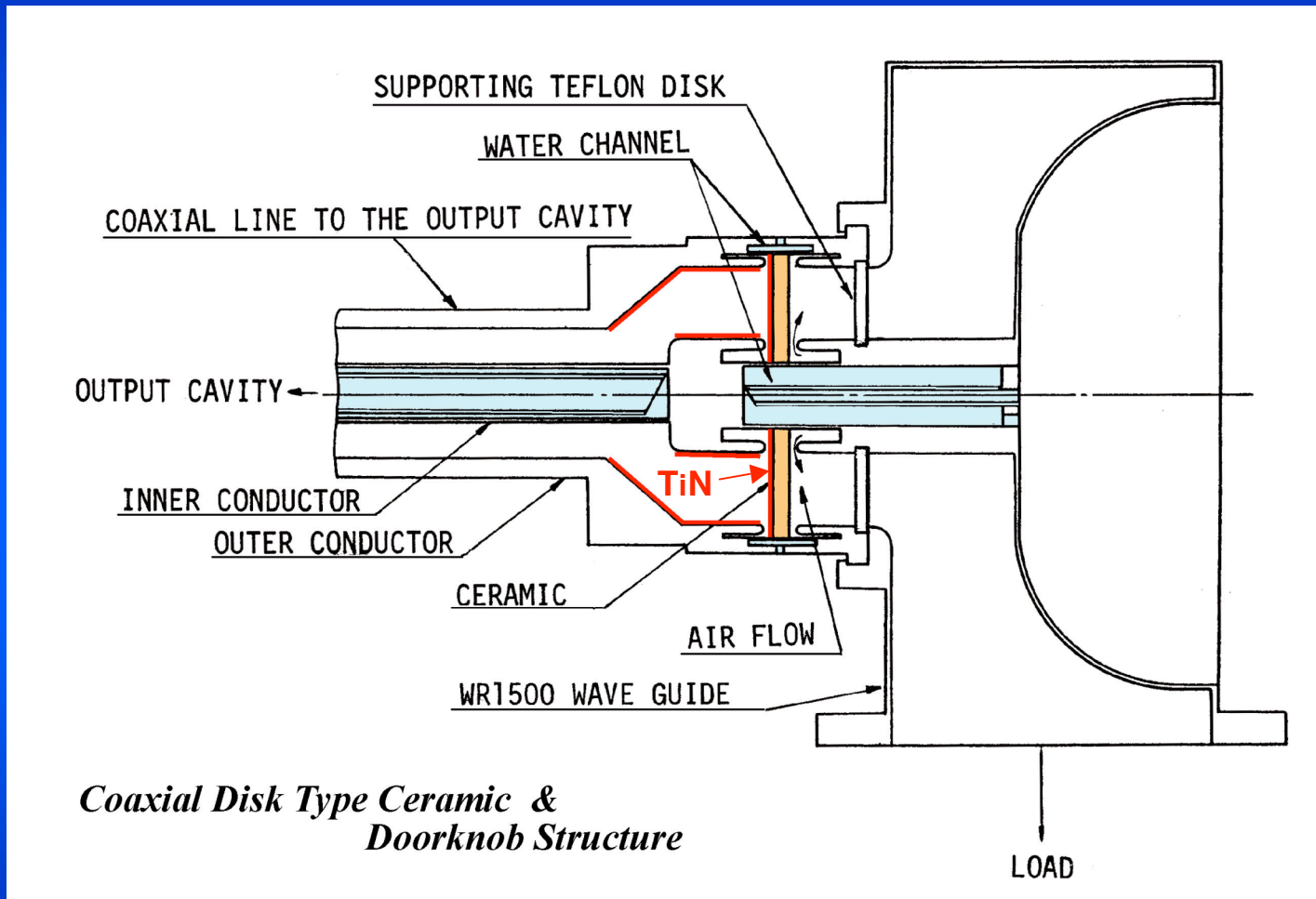
P_0 1.3MW, V_k 94.1kV, I_b 21.2A
 η 64.8%, VSWR of the load 1.07.
 Max η 65.5% at V_k 85.2kV for I_b 18.3A.



Performance of T41 as a function of beam voltage.

Klystron Output Coupler

The output coupler of our klystron is completely all right at the power level over 1.3 MW CW.



Key Techniques :

① Hybrid Cooling System

② Titanium Nitride Coating of Window Ceramics

Hybrid (Air & Water) Cooling System

μ WAVE OUTPUT

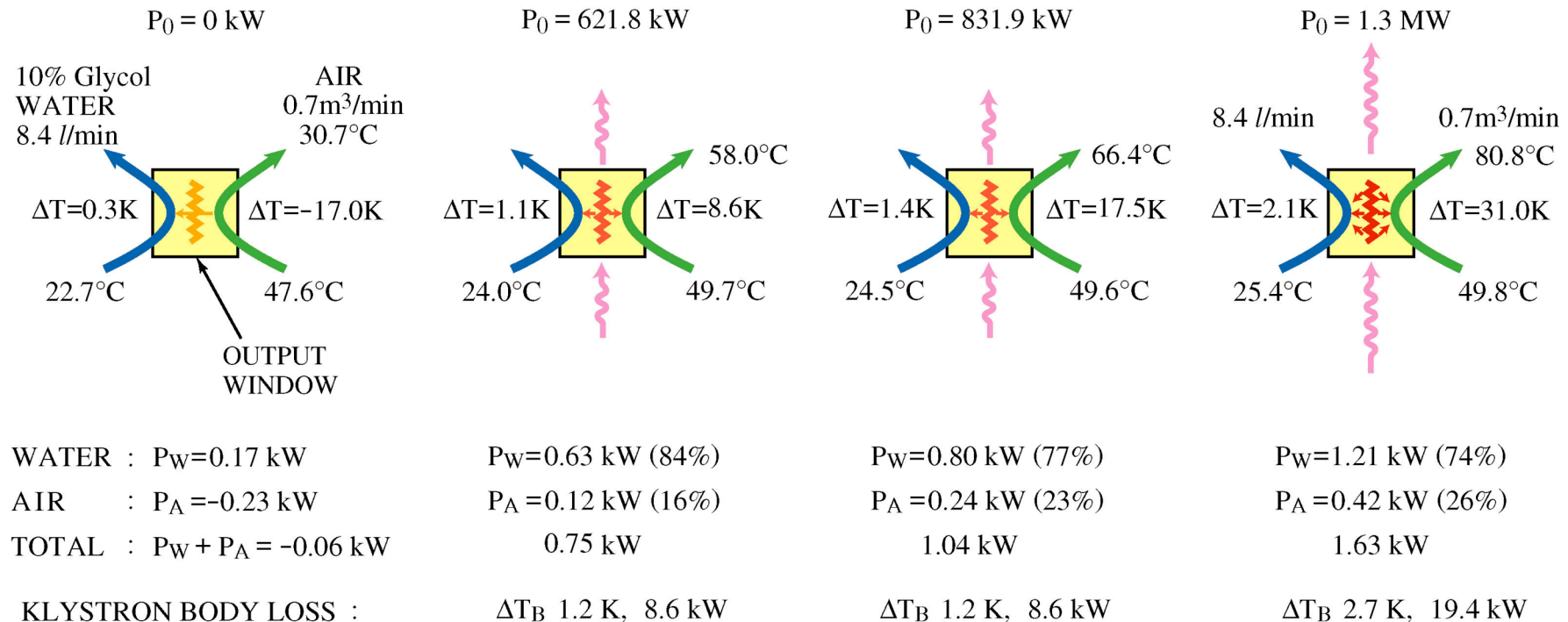


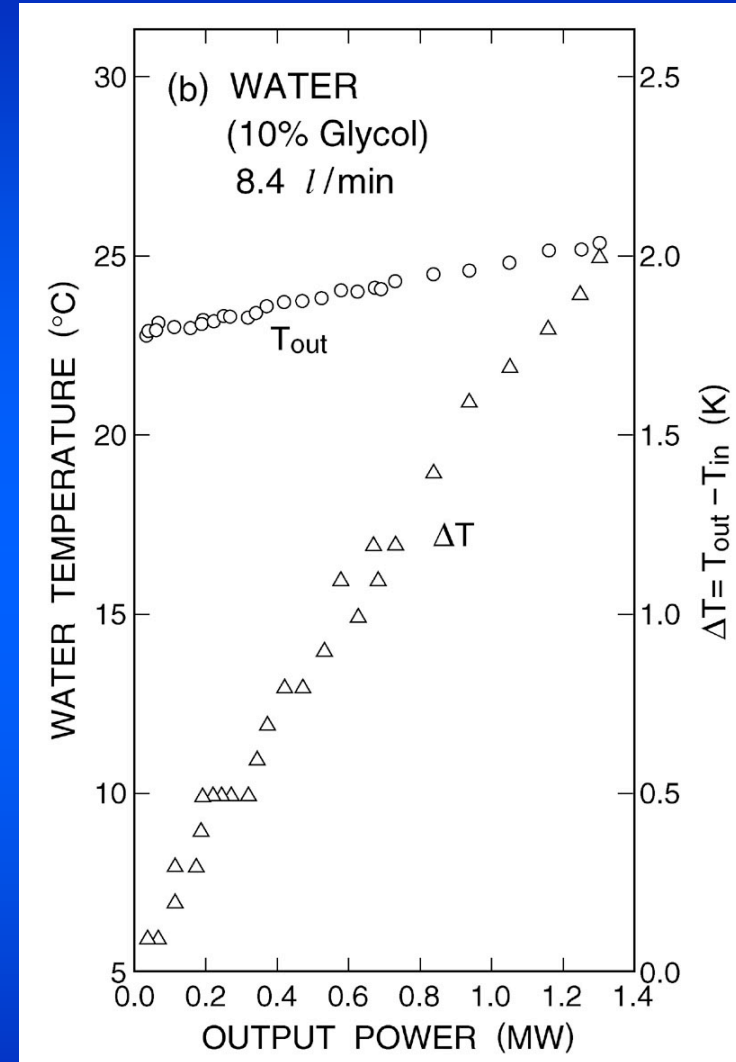
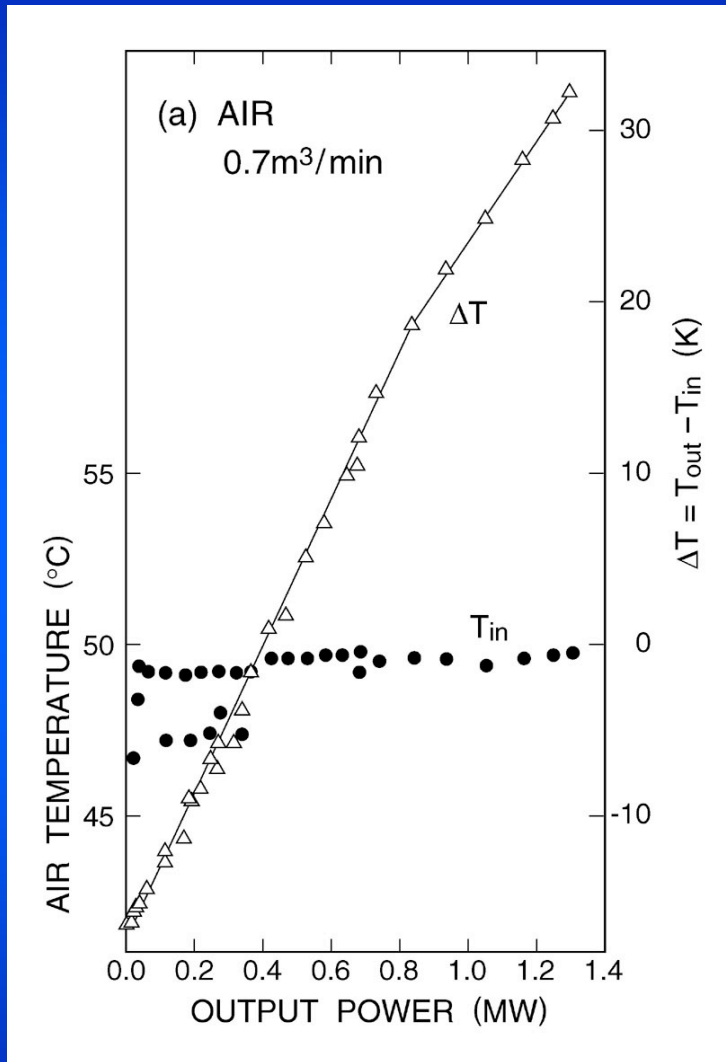
Figure summarizes power balance of the system.

At P_0 1.3 MW total power from window 1.63 kW, while body loss 19.4 kW.

About 26% of heat from window removed by air and 74% by water.

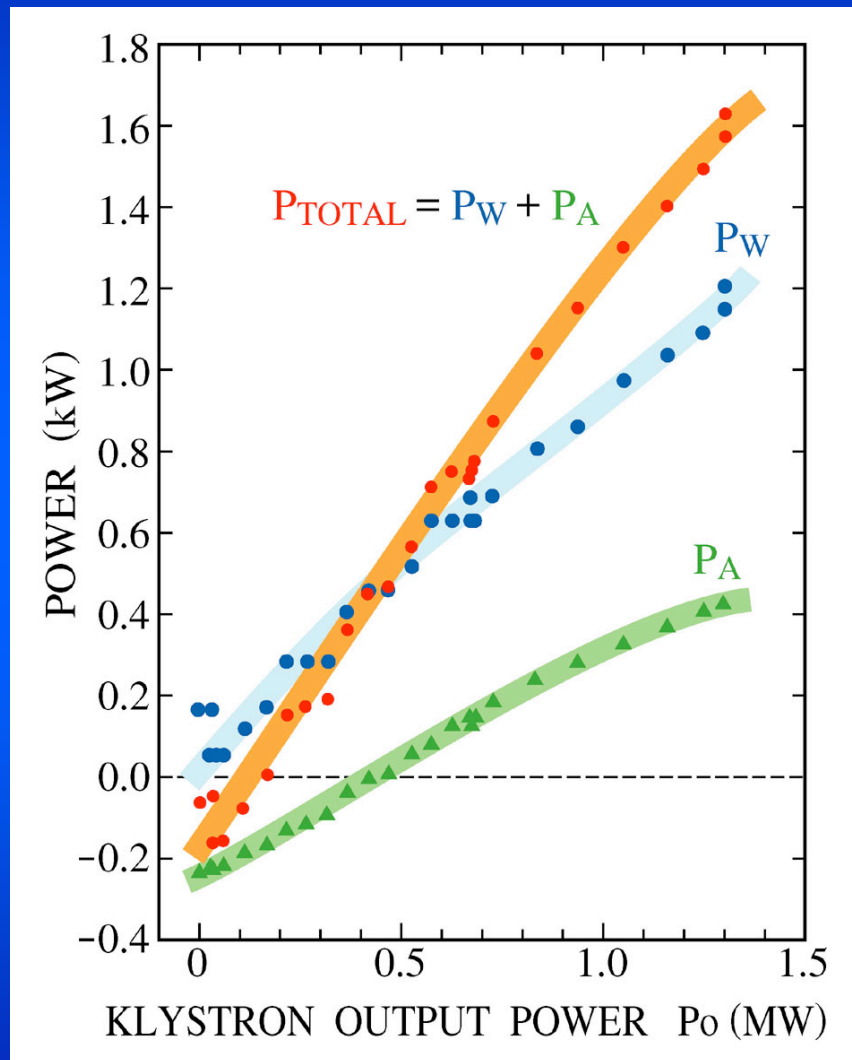
Ratio by air increases with rf power P_0 .

Linear Heating (1)



Temperature rise of (a) cooling air and (b) chiller cooling water containing 10% ethylene glycol as a function of klystron output power up to 1.3 MW.

Linear Heating (2)



Temperature rise
(Dissipated power) is
linear.

No abnormal increase

→ Heating mainly caused by
ceramic dielectric loss.

→ Multipactoring effectively
suppressed by TiN
coating.

Suppression of Multipactoring : Most Important Key Factor to Get Higher RF Power.

◎ Structure & quality of film depend on
coating method,
equipment used
and
coating conditions.

◎ In our case, DC Reactive Sputtering used.

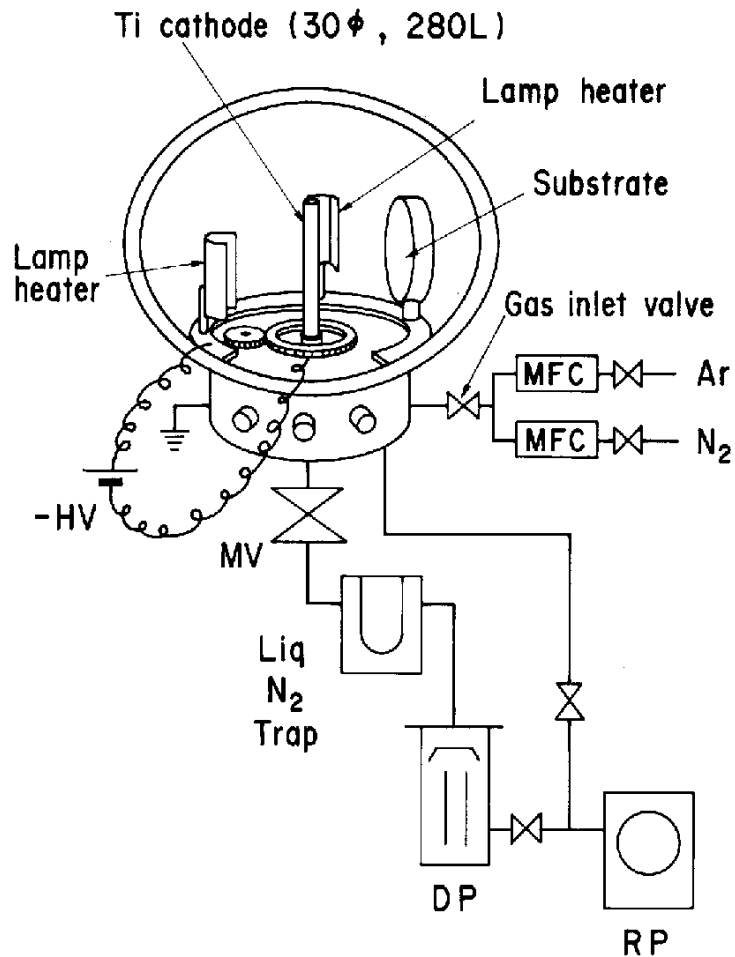
O₂ background high

Deposition rate low (1~3 Å / min)

→ TiN_xO_y rather than TiN_x formed with island and columnar structure.

→ Many weak links and High Resistivity.

DC Reactive Sputtering Method



Conditions of DC Reactive Sputtering of TiN_x

Samples	SSA-S (99.5% Al ₂ O ₃)
	1/4 CYLINDER, Lot #1 & #2 (ID 20mm, OD 25mm, L 200mm)
Preheating Time	30 min
Sample Temperature	About 150°C
Ultimate Pressure	2.5 x 10 ⁻⁵ Torr
Residual Gas Pressure after Preheating	2.2 x 10 ⁻⁵ Torr
Gas Flow Rate	
	Ar 31.3 SCCM
	N ₂ 11.1 SCCM
Total Working Pressure	6.2 x 10 ⁻² Torr
DC Output Power	3 kV
	60 mA
Distance between Ti and Substrates	56.2 mm
Deposition Rate	200 Å/h
Target Thickness	Various

Chamber updated.
DP replaced by CP afterwards.

No quality changes, however, observed.
—— We checked and confirmed it.

To Optimize Coating Conditions — Test Bench Developed at KEK Before.

KLYSTRON OUTPUT



DUMMY LOAD



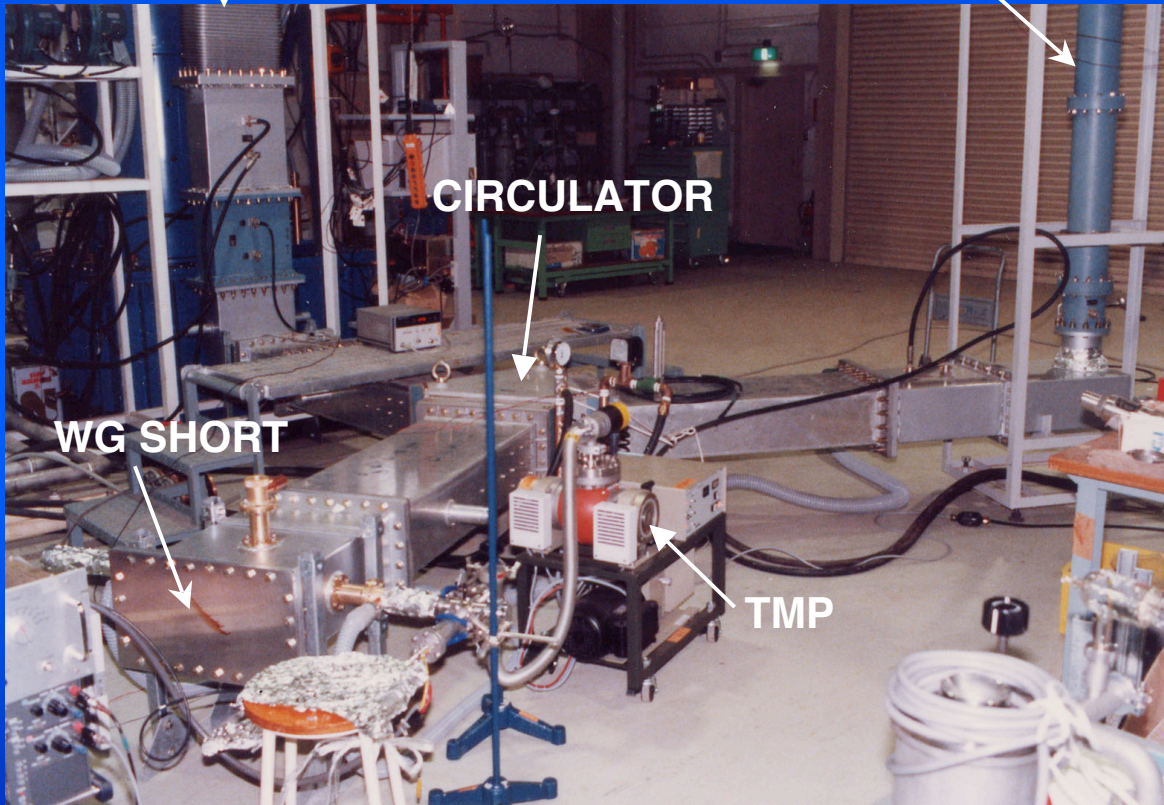
CIRCULATOR



WG SHORT



TMP

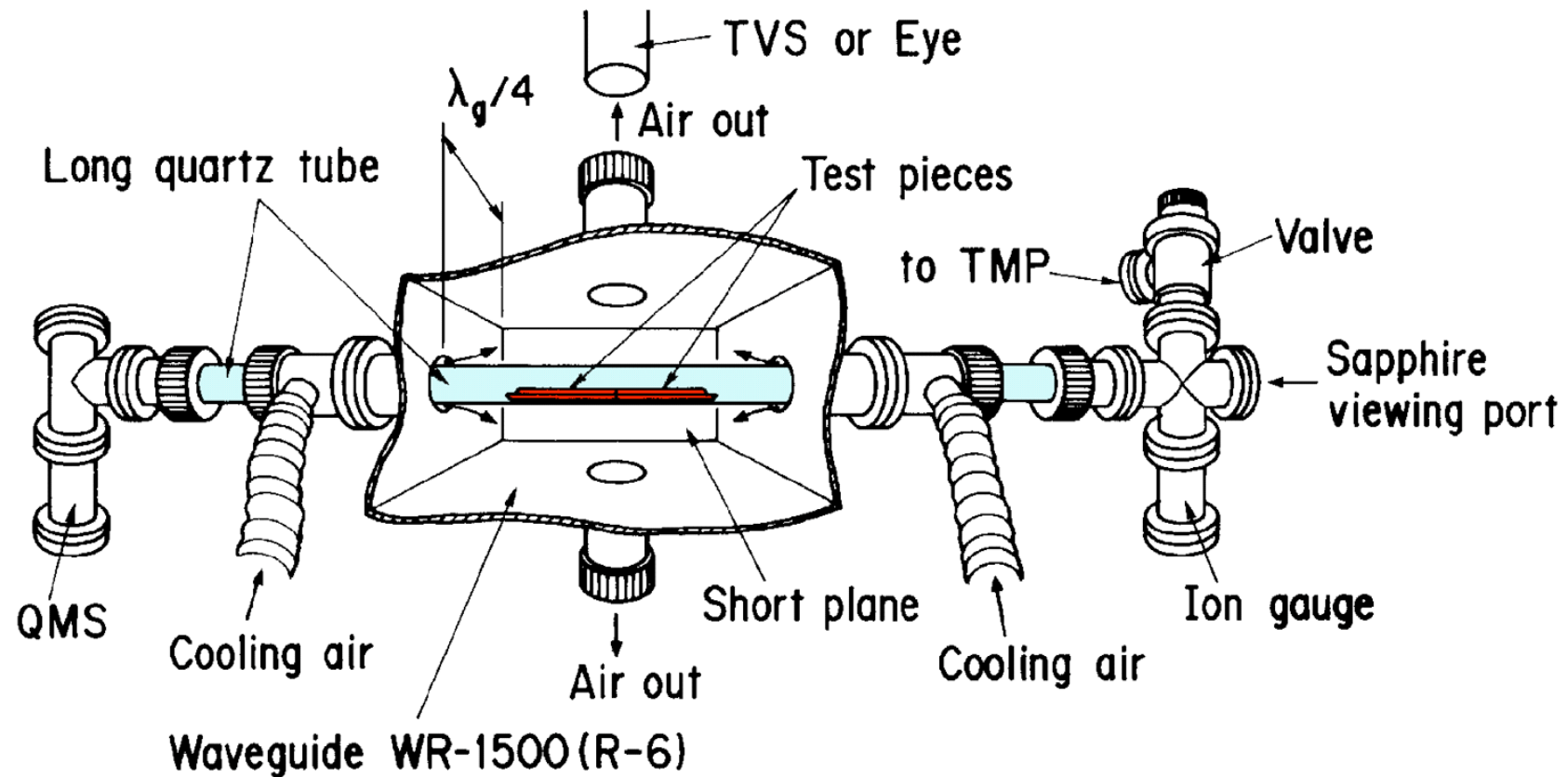


Experiments performed with Yasunao Takeuchi, KEK.

Klystron P_0 fed through Y shaped circulator and 100% reflected by WG short.

Ceramic tube or quartz tube placed at antinode position of WR1500 (R6) WG.

Small ceramic samples exposed to rf field in a quartz vacuum tube.

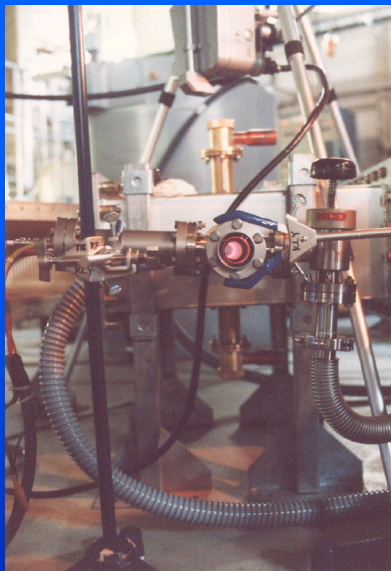


One can observe the tube and measure T from the top.
 One can also observe the inner view of the tube
 from the side viewing port made of sapphire.

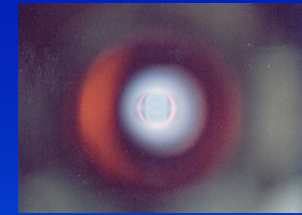
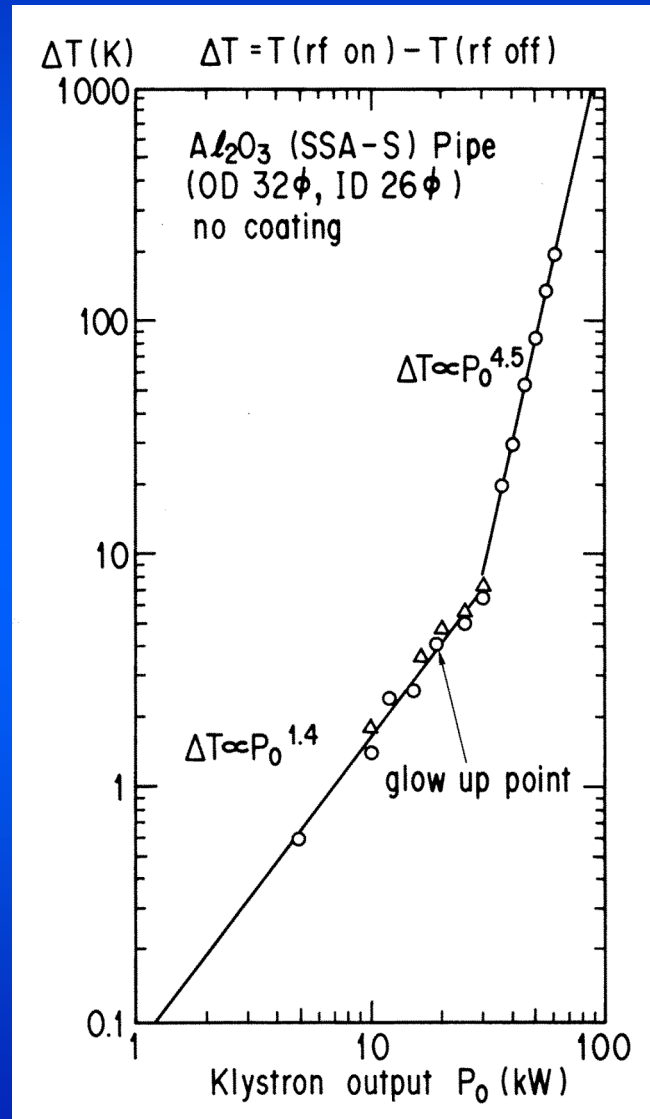
Temperature Increase Due to Multipactoring Caused by Large δ of Al_2O_3 .



Ceramic tube broken.

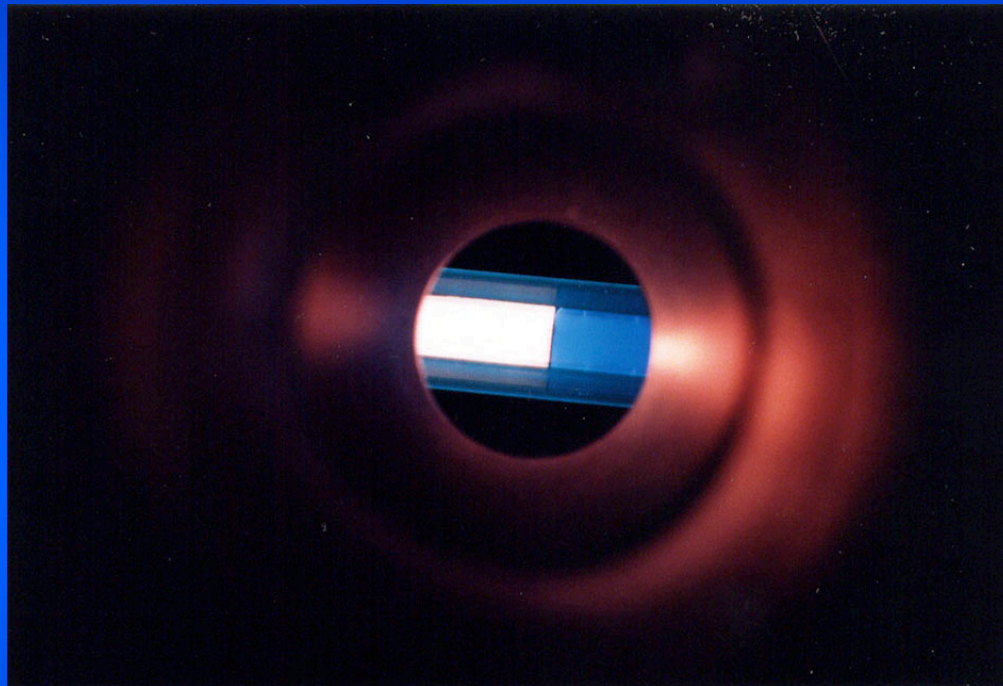


T measurement and side view of plasma.



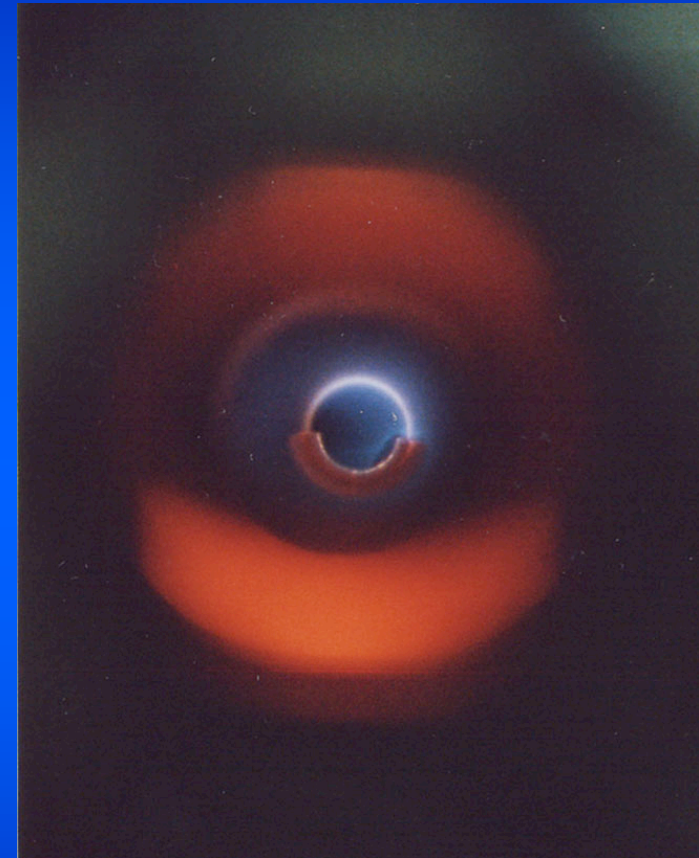
P_0
UP

Suppression of Multipactoring by TiN Coating.



Left sample
 Al_2O_3
without coating
(NC)

P_0 50 kW, P 3.2×10^{-6} Torr



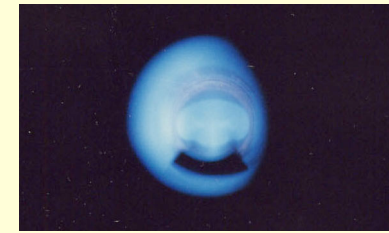
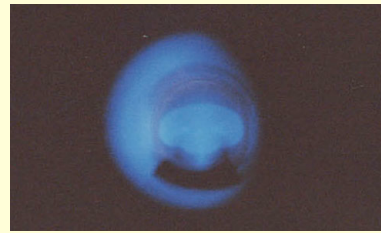
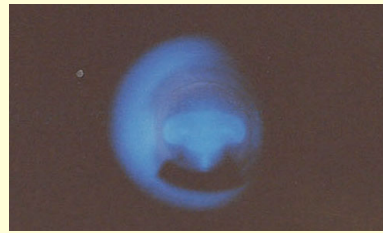
Right sample
 Al_2O_3
with 120 Å TiN

Left 100 Å TiN vs Right NC

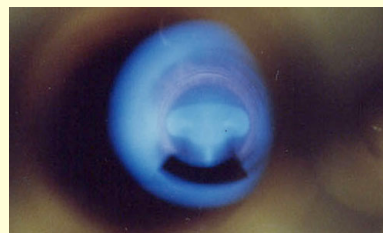
P_0 25.7 kW

Inner View of The Quartz Tube from The Side Viewing Port Made of Sapphire. Alumina Samples are Installed Inside.

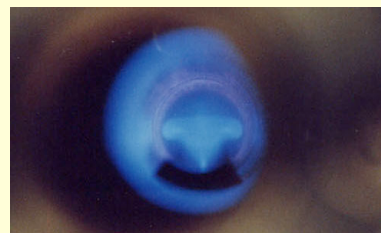
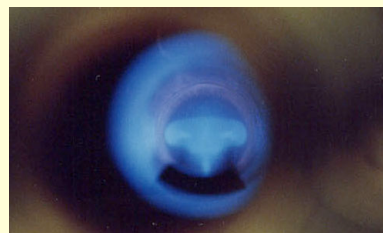
KLYSTRON POWER P_0 INCREASED



PLASMA GROWS UP

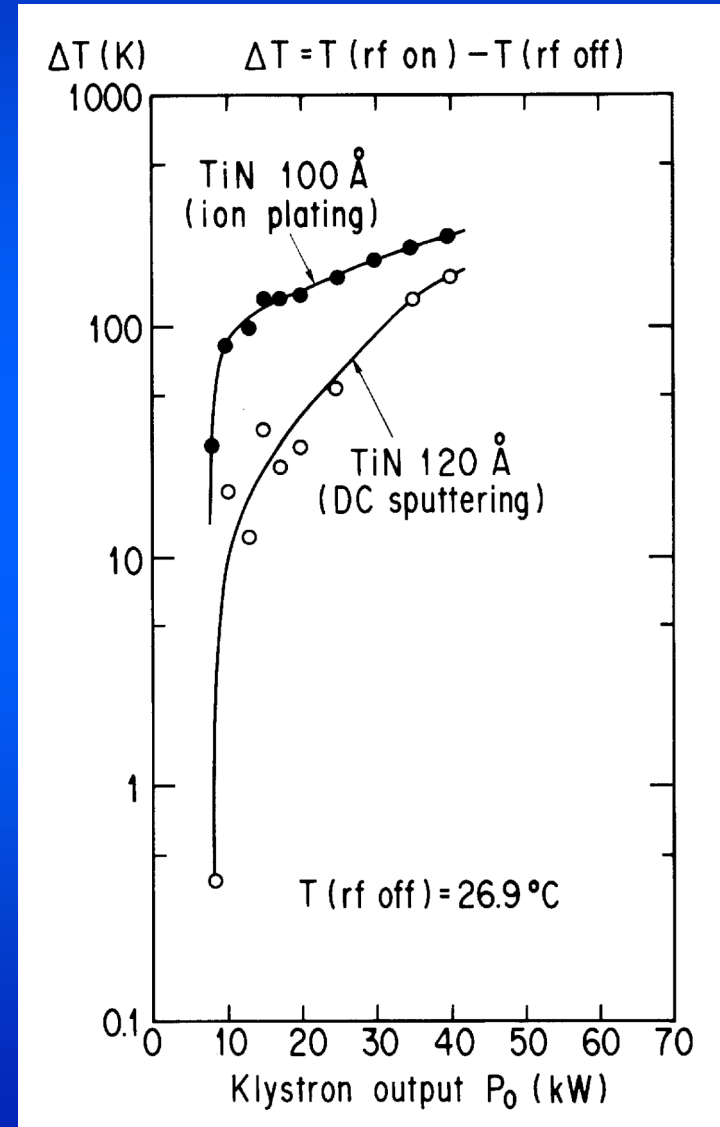
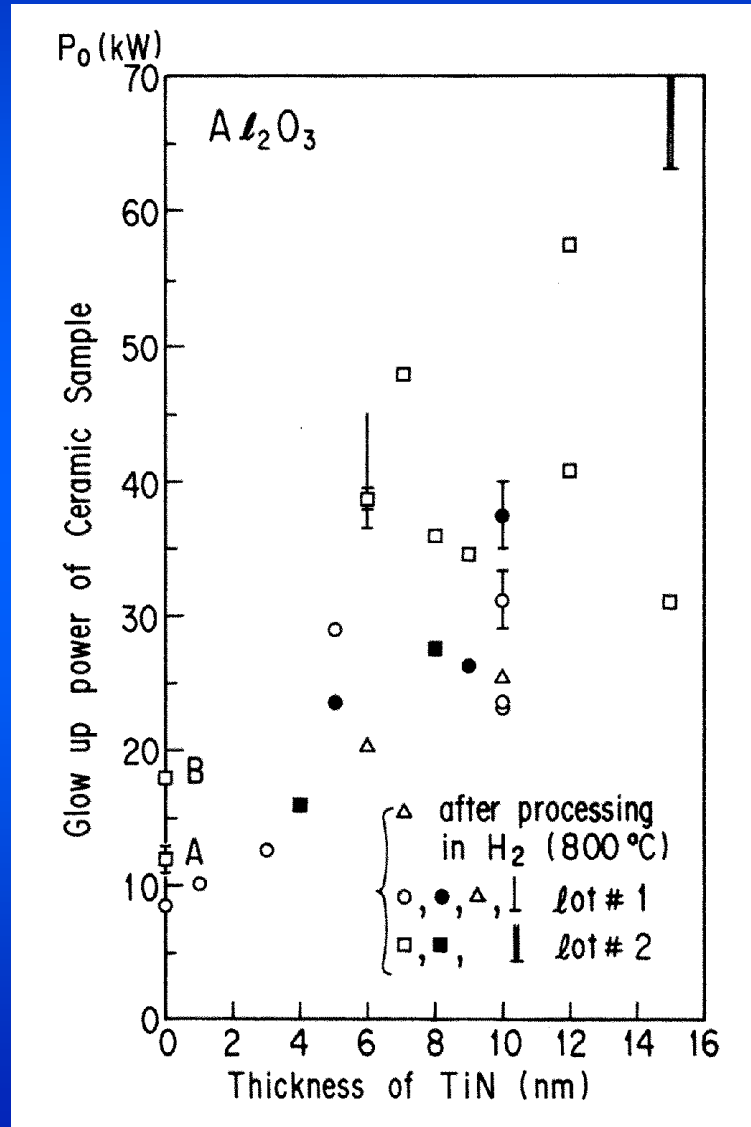


MAX P_0
PLASMA SHRINKS DOWN

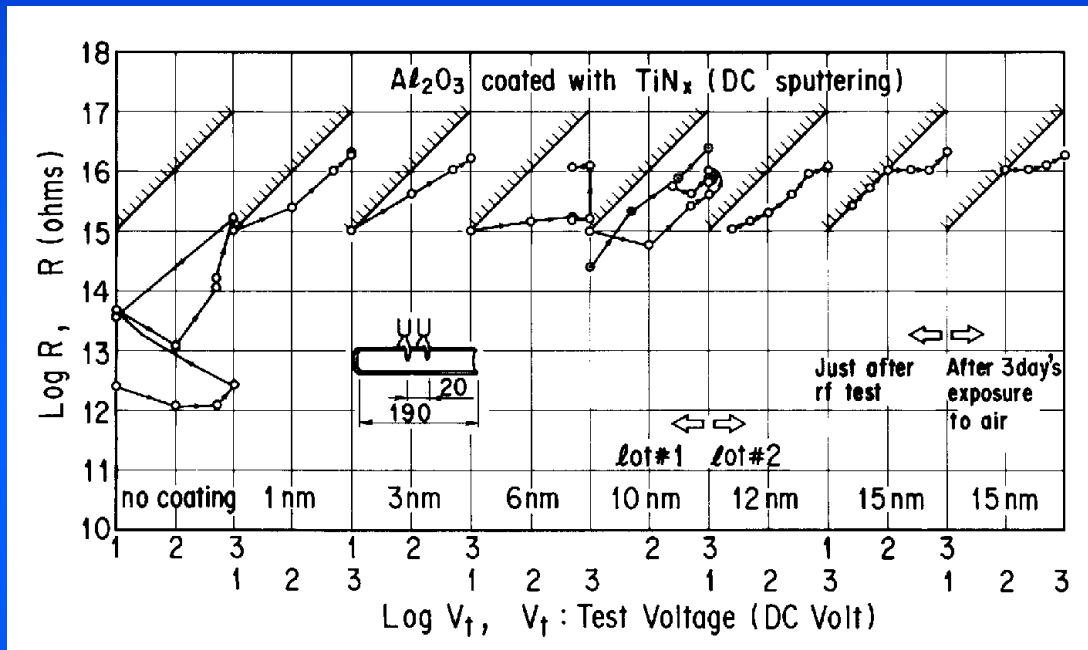


P_0 DECREASED

Optimum Coating Method and Optimum Thickness Determined by Bench Test.



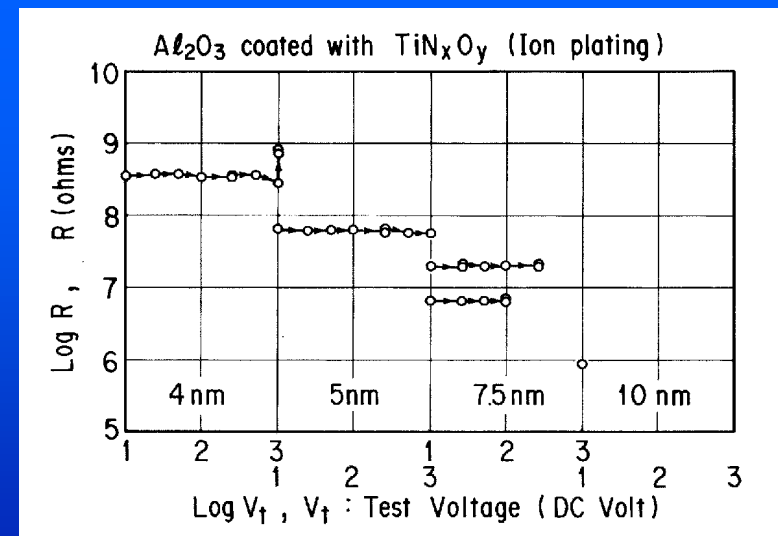
In Parallel, Measurements Were Also Made on DC Resistance of Standard Shaped Samples.



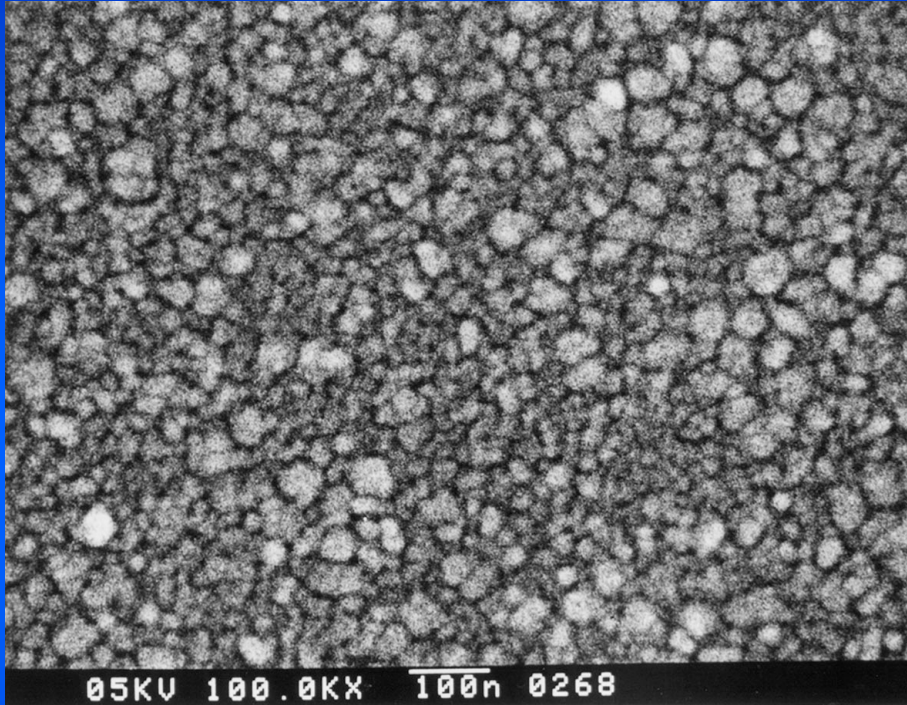
TiN_x (more precisely speaking, TiN_xO_yC_z)

e.g. x : 1.1, y : 2.3, z : 1.9

Oxygen intentionally added during plating.

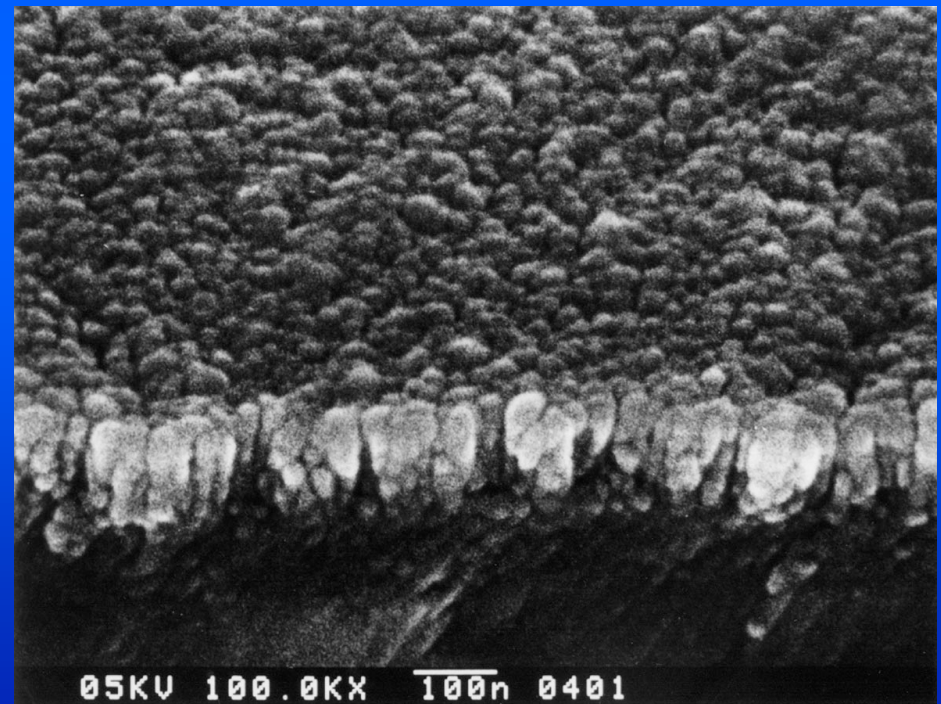


SEM Photos of Microscopic Structure of Our TiN_xO_y Films Coated on Al₂O₃ Substrates.



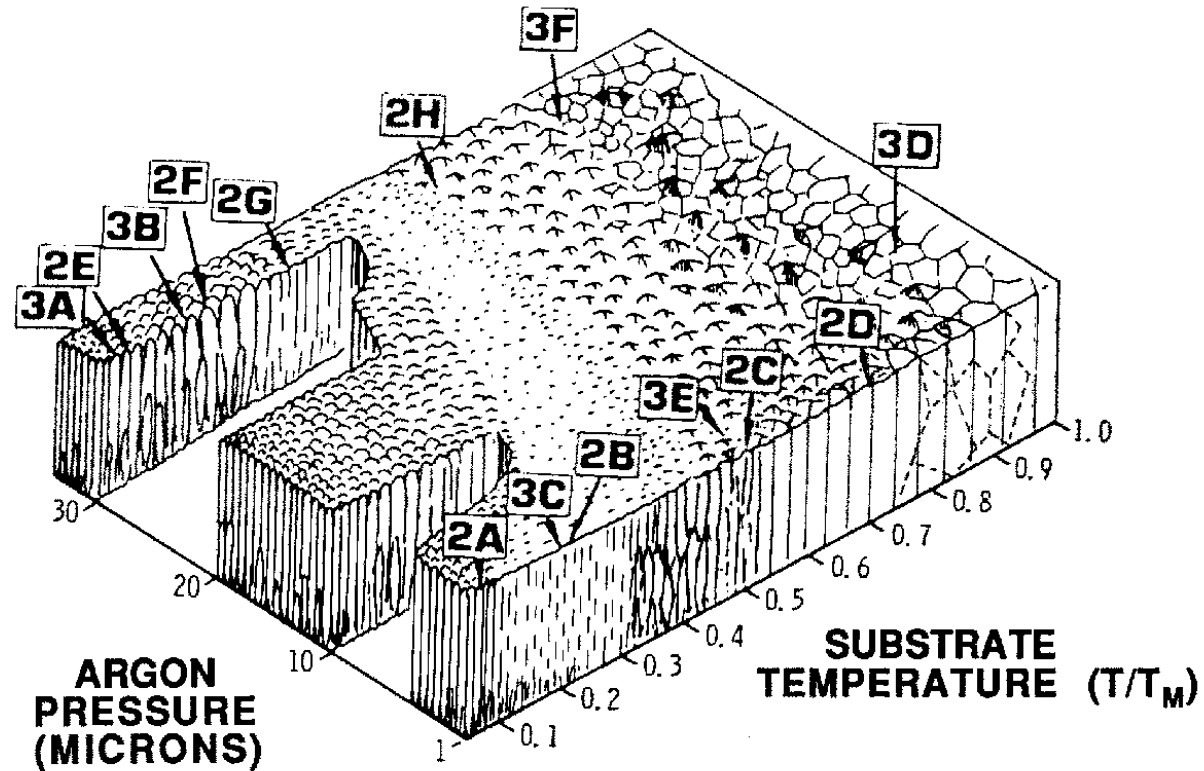
Very high resistivity is ensured by oxygen rich grain boundary layers of TiN_xO_y.

TiN grows up in island or columnar form.



Important Points about Anti-Multipactoring Coating :

- 1) Quality of film depends on equipment as well as method of coating. Samples made by DC reactive sputtering in HVac always superior to those by ion plating performed in oilless UHV system.**
- 2) TiN_xO_y is one of the best materials. R is very high and even increases with thickness and with exposure to rf field. Pure TiN is rather worse because of its high metallic conductivity.**
- 3) Optimum thickness for UHF use is 50~300 Å. The thicker, the better if it's below 150 Å . 60 Å is adopted for input couplers and T-tubes. 100 Å tried for V-tubes (KEK and LEP) and excellent results obtained, too.**



Schematic representation of dependence of coating structure on substrate temperature and argon pressure.

(Movchan - Demchishin - Thornton Model)

J. A. Thornton, J. Vac. Sci. Technol. 11, 666 (1974).

The effect of H₂ processing (800°C, 10min) on glow up point (P₀ in kW)

Specimen	Before processing	After processing	After rf aging
60Å TiN _x	≥ 36.2	18.7	20.3 ± 0.2 (rf 67min, max 45.3kW)
100Å TiN _x	23.3 ± 0.1	22.0	25.1 (rf 208min, max 60kW)
30Å CrO _x	28.0	21.5	21.5 (rf 77min, max 45.2kW)
50Å CrO _x	35.5 ± 2.5	20.7	21.0 (rf 100min, max 50kW)

RF aging is effective on TiN_x coating, but not on CrO_x coating.